## Notice of References Cited Application/Control No. O9/842,596 Examiner Sargon N Nano Applicant(s)/Patent Under Reexamination SHANTHAVEERAIAH ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

	Designant Number					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
	Α	US-6,633,538	10-2003	Tanaka et al.	370/222	
	В	US-6,792,479	09-2004	Allen et al.	710/10	
	С	US-6,016,144	01-2000	Blonstein et al.	715/791	
	D	US-5,959,994	09-1999	Boggs et al.	370/399	
	E	US-6,665,714	12-2003	Blumenau et al.	709/222	
	F	US-6,449,734	09-2002	Shrivastava et al.	714/15	
	G	US-6,654,752	11-2003	Ofek, Yuval	707/10	
	Н	US-				
	I	US-				
	J	US-				
	К	US-			•	
	L	US-				
	М	US-				

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν				·	
	0					
	Р					
	a					
	R					
	S					·
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.